



How to measure the invisible with the most accurate SIOS measurement systems

WEB-Seminar: Sept. 30, 2021, 08:30 AM / 3:30 PM CET, Berlin

Today's technological developments follow a common trend in many manufacturing industries: Products are becoming more complex and powerful, the demands on manufacturing quality are constantly increasing, while components and object structures are becoming smaller and more compact.

In turn, the increasing industrial use of micro- and nanotechnological objects leads to ever higher demands on the measurement technology used in manufacturing, verification and positioning. The tasks are realized on objects that are getting larger and larger, so that a link between the macro- and nano-worlds has to be made. Nanometrology is not only of great interest to the research or semiconductor industry, as a driver of the trend, it has long since found its way into areas such as nanoelectronics, microoptics, genetic engineering, molecular biology, materials research and many more.

In our approximately 45-minute webinar, you will learn how to measure the invisible with the most accurate measurement systems available from SIOS.

Our experts Dr. Denis Dontsov and Enrico Langlotz will provide information on the following main topics:

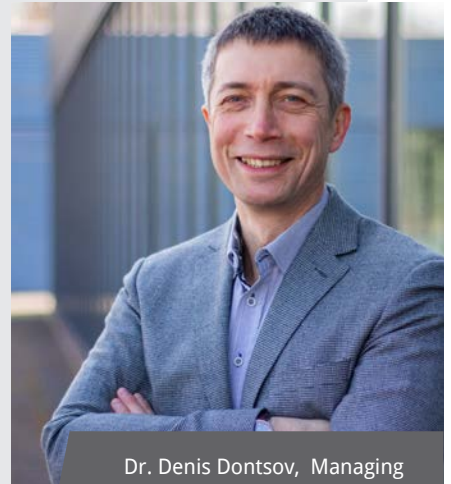
- ultra-stable high-resolution laser interferometers
- the basics of nanopositioning
- application of nanopositioning and nanomeasuring machine

Our speakers will be very happy to answer your questions about nanometrology after the presentation.

In our approximately 45-minute webinar, you will learn how to measure the invisible with the most accurate measurement systems available from SIOS. Our experts Dr. Denis Dontsov and Enrico Langlotz will provide information on the following main topics:

- Background of laser interferometry for nanometrology
- Nanomeasuring and Nanopositioning Maschine
- Principle of differential laser interferometers
- Applications for long range positioning with nanometer resolution

Our speakers will be very happy to answer your questions about nanometrology after the presentation.



Quick Info

Date: Thursday, Sept. 30, 2021

Time: 08:30 AM
3:30 PM CET, Berlin

Speaker: Dr. Denis Dontsov, Managing Director
Enrico Langlotz, R&D / Project Management,
Peter Grundschock, Sales Manager

Seminar venue: Online Clickmeeting

Language: English

Target group: measurement technicians, engineers, designers, quality managers, project managers and scientists

Industries: Metrology, nanopositioning, coordinate metrology, optics industry, precision instrumentation, research and development

We are looking forward to your participation and the dialogue with you.

[Online registration](#)

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